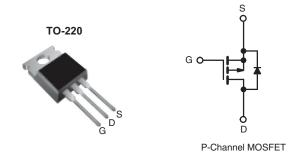


Power MOSFET

PRODUCT SUMMARY				
V _{DS} (V)	- 100			
$R_{DS(on)}\left(\Omega\right)$	V _{GS} = - 10 V	0.20		
Q _g (Max.) (nC)	61			
Q _{gs} (nC)	14			
Q _{gd} (nC)	29			
Configuration	Single			



FEATURES

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- P-Channel
- 175 °C Operating Temperature
- · Fast Switching
- · Ease of Paralleling
- Simple Drive Requirements
- Lead (Pb)-free Available

DESCRIPTION

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 W. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.

ORDERING INFORMATION	
Package	TO-220
Load (Dh) from	IRF9540PbF
Lead (Pb)-free	SiHF9540-E3
SnPb	IRF9540
SIFD	SiHF9540

PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V_{DS}	- 100	V	
Gate-Source Voltage			V_{GS}	± 20		
Continuous Drain Current	V_{GS} at - 10 V $\frac{T_C = 2}{T_C = 10}$	5 °C		- 19		
Continuous Diain Current	$T_C = 10$	00 °C	I _D	- 13	Α	
Pulsed Drain Current ^a			I _{DM}	- 72		
Linear Derating Factor				1.0	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	640	mJ	
Repetitive Avalanche Current ^a			I _{AR}	- 19	Α	
Repetitive Avalanche Energy ^a			E _{AR}	15	mJ	
Maximum Power Dissipation	T _C = 25 °C		P_D	150	W	
Peak Diode Recovery dV/dt ^c			dV/dt	- 5.5	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	- 55 to + 175	- °C	
Soldering Recommendations (Peak Temperature)	for 10 s			300 ^d	7	
Mounting Torque	6-32 or M3 screw			10	lbf ⋅ in	
				1.1	N · m	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. V_{DD} = 25 V, starting T_J = 25 °C, L = 2.7 mH, R_G = 25 Ω , I_{AS} = 19 A (see fig. 12).
- c. $I_{SD} \leq$ 19 A, $dI/dt \leq$ 200 A/µs, $V_{DD} \leq V_{DS}, \, T_{J} \leq$ 175 °C.
- d. 1.6 mm from case.

^{*} Pb containing terminations are not RoHS compliant, exemptions may apply



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R _{thJA}	-	62		
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.50	-	°C/W	
Maximum Junction-to-Case (Drain)	R _{thJC}	-	1.0		

PARAMETER	SYMBOL	TEST	MIN.	TYP.	MAX.	UNIT	
Static							
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0	- 100	-	-	V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	Reference to 25 °C, I _D = - 1 mA		- 0.087	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V$	' _{GS} , I _D = - 250 μA	- 2.0	-	- 4.0	V
Gate-Source Leakage	I _{GSS}	V _{GS} = ± 20 V		-	-	± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}		V _{DS} = - 100 V, V _{GS} = 0 V V _{DS} = - 80 V, V _{GS} = 0 V, T _J = 150 °C		-	- 100 - 500	μΑ
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = - 10 V	I _D = - 11 A ^b	-	-	0.20	Ω
Forward Transconductance	9 _{fs}	V _{DS} = - 50 V, I _D = - 11 A ^b		6.2	-	-	S
Dynamic					•		,
Input Capacitance	C _{iss}	$V_{GS} = 0 \text{ V},$ $V_{DS} = -25 \text{ V},$ f = 1.0 MHz, see fig. 5		-	1400	-	pF
Output Capacitance	C _{oss}			-	590	-	
Reverse Transfer Capacitance	C _{rss}			-	140	-	
Total Gate Charge	Qg		$V_{GS} = -10 \text{ V}$ $I_D = -19 \text{ A}, V_{DS} = -80 \text{ V},$ see fig. 6 and 13 ^b	-	-	61	nC
Gate-Source Charge	Q _{gs}	V _{GS} = - 10 V		-	-	14	
Gate-Drain Charge	Q _{gd}			-	-	29	
Turn-On Delay Time	t _{d(on)}	$V_{DD} = 50 \text{ V, } I_D = 19 \text{ A,}$ $R_G = 9.1 \Omega, R_D = 2.4 \Omega, \text{ see fig. } 10^b$		-	16	-	ns
Rise Time	t _r			-	73	-	
Turn-Off Delay Time	t _{d(off)}			-	34	-	
Fall Time	t _f			-	57	-	
Internal Drain Inductance	L_D	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	nЦ
Internal Source Inductance	L _S			-	7.5	-	nH
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		1	-	- 19	Α
Pulsed Diode Forward Current ^a	I _{SM}			-	-	- 72	
Body Diode Voltage	V _{SD}	T _J = 25 °C, I _S = - 19 A, V _{GS} = 0 V ^b		-	-	- 5.0	V
Body Diode Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = - 19 A, dl/dt = 100 A/μs ^b		-	130	260	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	0.35	0.70	μC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by			V Le and	[D)	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width $\leq 300~\mu s;$ duty cycle $\leq 2~\%.$



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

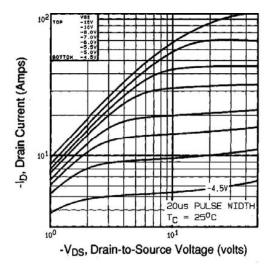


Fig. 1 - Typical Output Characteristics, T_C = 25 $^{\circ}C$

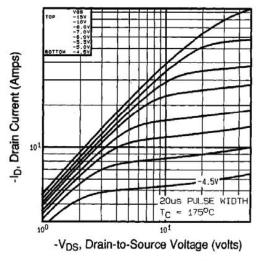


Fig. 2 - Typical Output Characteristics, T_C = 175 $^{\circ}$ C

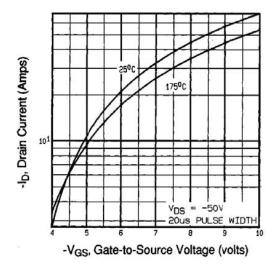


Fig. 3 - Typical Transfer Characteristics

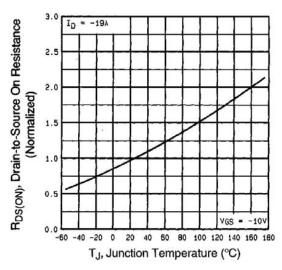


Fig. 4 - Normalized On-Resistance vs. Temperature



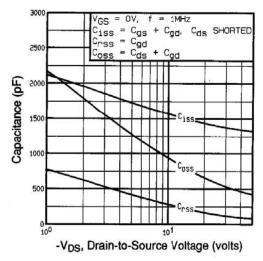


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

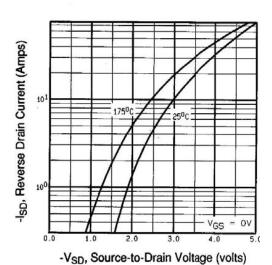


Fig. 7 - Typical Source-Drain Diode Forward Voltage

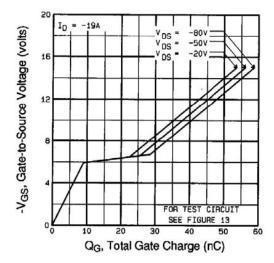


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

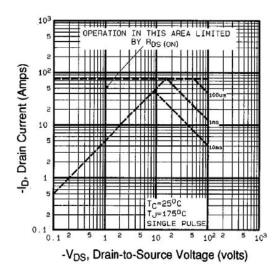


Fig. 8 - Maximum Safe Operating Area



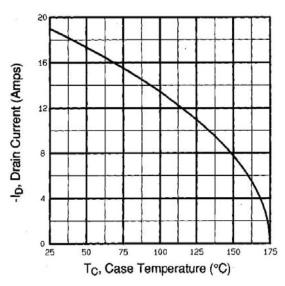


Fig. 9 - Maximum Drain Current vs. Case Temperature

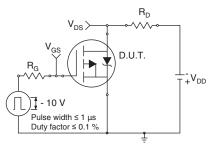


Fig. 10a - Switching Time Test Circuit

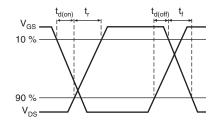


Fig. 10b - Switching Time Waveforms

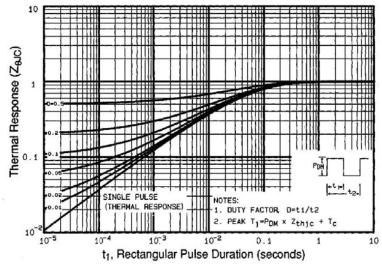


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

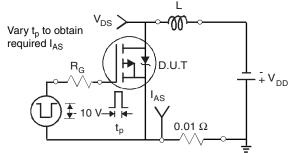


Fig. 12a - Unclamped Inductive Test Circuit

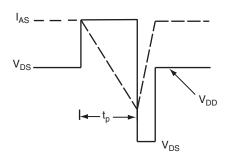


Fig. 12b - Unclamped Inductive Waveforms



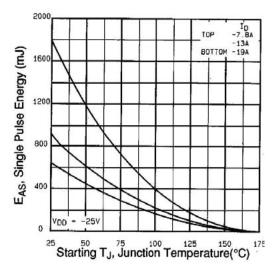


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

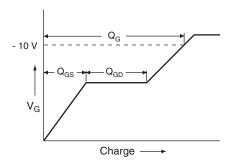


Fig. 13a - Basic Gate Charge Waveform

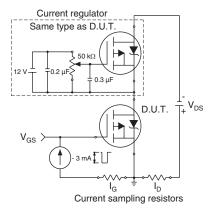
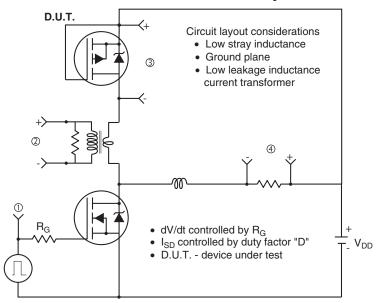


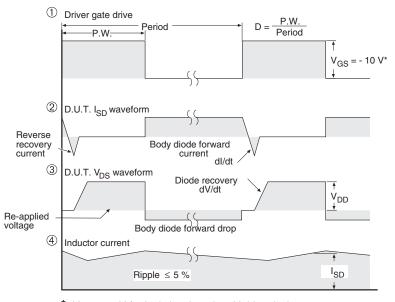
Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit



• Compliment N-Channel of D.U.T. for driver



* V_{GS} = - 5 V for logic level and - 3 V drive devices

Fig. 14 - For P-Channel

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